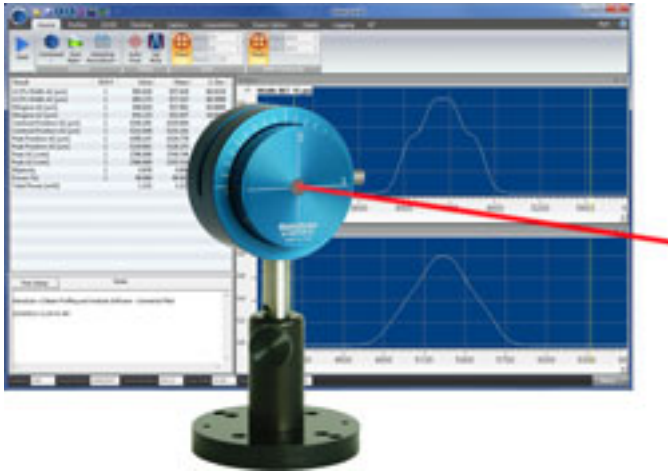


Scanning Slit Laser Beam Profiler



Ophir Photonics has introduced the NanoScan 2, a NIST-calibrated scanning slit laser beam profiler. The NanoScan 2 measures continuous wave (CW) and pulsed laser beams across the entire spectral range, from UV to far infrared.

The system features a USB2 interface that provides deep, 12-bit digitization of the signal for enhanced dynamic range up to 35 dB power. An enhanced digital controller improves the accuracy and stability of measurements; beam size and beam pointing can be measured with a 3 sigma precision of several hundred nanometers. The NanoScan 2 also features software controllable scan speed and a “peak-connect” algorithm that allow measurement of pulsed and pulse width modulated lasers with frequencies of a few kHz and higher with any detector. The ability to alter the drum speed helps increase the dynamic range, allowing a larger operating space for any scanhead.

The NanoScan 2 system uses moving slits to measure beam sizes from microns to centimeters at beam powers from microwatts to kilowatts, without attenuation. Detector options—silicon, germanium, and pyroelectric technologies—allow measurement at wavelengths from ultraviolet to far infrared.

Ophir Photonics, www.ophiropt.com [1]

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